## D o Therm oelectric M aterials in N ano junctions D isplay M aterial P roperty or Junction P roperty?

Yu-Chang Chen and Yu-Shen Liu

Department of Electrophysics, National Chiao Tung University, 1001 Ta H such Road, H sinchu 30010, Taiwan

The miniaturization of them oelectric nano junctions raises a fundam ental question: do the therm oelectric quantities of the bridging materials in nano junctions remain to display material properties or show junction properties? In order to answer this question, we investigate the Seebeck coe cient S and the them oelectric gure of merit Z T especially in relation to the length characteristics of the junctions from the rst-principles approaches. For S, the metallic atom ic chains reveal strong length characteristics related to strong hybridization in the electronic structures between the atom s and electrodes, while the insulating molecular wires display strong material properties due to the cancelation of exponential scalings in the D O Ss. For Z T, the atom ic wires remain to show strong junction properties. However, the length chrem atistics of the insulation molecular wires depend on a characteristic temperature  $T_0 = \sqrt{=(1)}$  around 10 K .W hen T  $T_0$ , where the electron transport dom inates the them all current, the molecular junctions display junction properties.

Nanoscale therm celectric devices can be considered as the new types of devices which can be embedded into integrated chip sets to assist the stability of devices by converting the accumulated waste heat into useful electric energy. There has been an ever increasing interest in the therm celectric properties of nano junctions [1, 2, 3, 4, 5, 6, 7, 8, 9, 10], partially motivated by the recent experim ents dem onstrating the capability of m easuring the Seebeck coe cients in the molecular junctions [11, 12]. As the Seebeck coe cients are relevant not only to the magnitude but also to the slope of density of states (DOSs), they can reveal more detailed inform ation about the electronic structures of the materials sandwiched in the nanojunctions beyond what the conductance m easurem ents can provide. The Seebeck coe cients have been applied to explore the electronic structures of m olecular junctions using functional substitutions for the bridging m olecules [10, 12]. Theorists have proposed using gate elds and external biases as m eans to m odulate the Seebeck coe cients in nano junctions [2, 3, 10]. Much research has been devoted to the study of Seebeck coe cients [1, 2, 3, 4, 5, 6, 7, 8, 9, 10], but little is known about the fundam ental therm oelectric properties in nano junctions.

Indeed, the miniaturization of them oelectric nanojunctions raises a fundam ental question: does bridging them oelectric material in nano junctions show material properties or junction properties? Them oelectric bulk crystals usually show material properties, where the thermoelectric physical quantities are irrelevant to the sizes and shapes of materials. In addition, recent experiments on Seebeck coe cients in molecular junctions also reveal strong signals of material properties. These experiments have observed that Seebeck coe cients are insensitive to the number of molecules in junctions and show rather weak dependence on the lengths of the bridging molecules, which is in sharp contrast to the conductance which shows strong exponential dependence on the lengths of molecules [11, 12, 13]. However, the bridging materials in nanojunctions may have strong interactions with the contacts. From this point of view one can say them oelectric quantities can display the junction characteristics. Considering the examples and the reason quoted above, it is therefore not obvious whether the therm oelectric quantities of the bridging materials in nanojunctions display junction properties or material properties.

In this letter, we will show that the therm oelectric quantities in nanojunctions unnecessarily display entire m aterial properties or junction properties. To demonstrate this point, this study investigates two important therm oelectric quantities, the Seebeck coe cient (S) and the therm oelectric gure of merit (Z T), in (m etallic) alum inum atom ic junctions and (insulating) m olecular junctions. It shows that m etallic atom ic chains reveal strong junction properties while the insulating m olecular wires partially possess the m aterial properties, where S reveals them aterial property and Z T displays the junction property at tem peratures larger than the characteristic tem – perature  $T_0$ .

To answer the question, we have developed a theory with analytical expressions for S and Z T allied to a fully self-consistent st-principles calculation in the fram ework of the density functional theory (DFT). It allows us to num erically calculate S and Z T and subsequently investigate these quantities analytically. W e focus on the subject on whether S and ZT depend on the characteristics of the junctions, especially on the dependence on length-characteristic of junctions. Before turning to the detailed discussion, let us begin with a brief introduction on how to calculate S and ZT. First, we consider that the junction consists of source-drain electrodes, with distinct chem ical potentials  $_{L(R)}$  and tem peratures  $T_{L(R)}$ , as independent electron and phonon reservoirs. W hen an additional in nitesim altem perature T is applied across the junction, an extra voltage V is induced to com pensate the electric current induced by the tem perature gradient T across the junction. We then derive the

expressions for S (de ned as S = V = T) and the electron them al conductance (de ned as  $_{e1} = J_Q^{e1} = T$ ), where  $J_Q^{e1}$  is the therm all current conveyed by the electrons which also carry the electric current).

$$S = \frac{1}{e} \frac{K_{1}^{L} + K_{1}^{R}}{K_{0}^{L} + K_{0}^{R}}; \qquad (1)$$

$$h_{\text{el}} = \frac{1}{h} \frac{X}{\sum_{i=L;R}} (K_{1}^{i} \text{eS} + \frac{K_{2}^{i}}{T_{i}}); \qquad (2)$$

<sup>n</sup>  $\frac{\text{Of}_{E}^{L(R)}}{\text{OF}}$  (E), and where  $K_n^{L(R)} = \frac{R}{dE} E$ L (R ) the transmission function (E) =  $\left( \stackrel{R}{(E)} \right) = \left( \stackrel{L}{(E)} \right)$ , which is a direct consequence of the time-reversal symmetry. It has been assumed that the left and right electrodes serve as independent electron and phonon reservoirs where the electron population is described by the Ferm i-Dirac distribution function,  $f_{\scriptscriptstyle\rm E}^{{\rm L}~(R\,)}$  = 1= exp  $E_{\rm L~(R\,)}$  =k\_B  $T_{\rm L~(R\,)}$  + 1 , and  $k_B$ is the Boltzm ann constant. The transm ission functions are computed using the wave functions obtained selfconsistently in the DFT fram ework [14, 15]. We should notice that the above equations are suitable for describing S and el in nano junctions operated under nite external biases, where two electrodes can have di erent tem peratures.

In addition, the di erential conductivity, typically insensitive to temperature in cases where direct tunneling is the major transport mechanism, can be expressed as

$$= \frac{e^{2}}{2} dE \int_{i=L,R}^{L} f_{E}^{i} (1 f_{E}^{i}) (E) = k_{B} T_{i}: \quad (3)$$

So far, the physical quantities (S, , and  $_{el}$ ) which have been discussed are related to the electron transport . It must be noted that the heat current is conveyed by the electrons and phonons simultaneously. The phonon therm al conductance ( $_{ph}$ ) usually dominates the com – bined therm al conductance =  $_{el} + _{el}$  at large tem – peratures. The complete discussion on Z T shall include the essential ingredient  $_{ph}$ ; thus Z T can be expressed as follow s:

$$ZT = \frac{S^2}{el + ph}T; \qquad (4)$$

where  $T = (T_{\rm L} + T_{\rm R})=2$  is the average temperature of the source-drain electrodes. We estimate the phonon therm alconductance following the approaches of P atthon and G eller [16]. It is assumed that the nanojunction is a weak elastic link, with a given sti ness which can be evaluated from the total energy calculations, attached to the electrodes modeled as phonon reservoirs. The phonon therm al conductance (de ned by  $k_{\rm ph} = J_{\rm Q}^{\rm ph} = T$ ) is given by:

$$_{\rm ph} = \frac{K^2}{\sim k_{\rm B}}^{\rm Z} \quad dE \ E^2 N_{\rm L} \ (E) N_{\rm R} \ (E) \sum_{i=L,R}^{\rm X} \frac{n_i (E) (1 + n_i (E))}{T_i^2}$$
(5)

where  $n_{L(R)} = 1 = [exp(E = k_B T_{L(R)}) 1]$  and  $N_{L(R)}(E)$ C E is the Bose-E instein distribution function and the spectral density of phonon states in the left (right) electrode, respectively. The sti ness of the bridging nanostructure is K = YA=1, where Y is the Young's modulus and A (1) is its cross-section (length).

We have numerically computed S and ZT using Eqs. (1) to (5) allied to the transmission functions obtained self-consistently in the DFT framework, as shown in Figs. 1 and 2. To elaborate the properties of the Seebeck coeccient and the the therm celectric gure of merit, we will limit our discussion to the linear response regime (i.e.,  $_{\rm L}$   $_{\rm R}$  = ) and T $_{\rm L}$  = T $_{\rm R}$  = T. After expanding S, el, and ph in term softhe temperature T, we obtain the analytical expressions for the S and ZT.

where =  ${}^{2}k_{B}^{2}\frac{(0 - 1)}{(0 - 1)} = (3e ())$ . We have noted that the Seebeck coe cient depends on the magnitude and the slope of the transmission function, and is linearly proportional to T at low temperatures.

$$ZT = \frac{2 T^{3}}{T + (1)T^{3}};$$
 (7)

where we have expanded el and ph up to the lowest order in tem peratures as  $_{el}$  T and  $_{ph}$  (1)T<sup>3</sup>. The prefactor and (1) are =  $2 \frac{k_B^2}{k_B^2}$  ()=(3h) and (1) = 8  ${}^{5}k_{B}^{4}C^{2}A^{2}Y^{2}=(15\sim l^{2})$ , respectively. One may notice that there is a characteristic tem perature  $T_0 = 1 = (1)$ , which is around 10 K for the alkanethiolm olecular junctions and is negligibly small for alum inum atom ic junc- $T_{0}\,\text{,}\,$  the electron therm al conductions. W hen T  $S^2T = k_{el}$  $^{2} = T^{2}$ , tance dom inates and ZT which is irrelevant to the length-characteristic of the junction and is proportional to T<sup>2</sup> as tem peratures increase. W hen T T<sub>0</sub>, the phonon therm al conductance dom inates and ZT tends to have a saturation value of  $S^2T = ph$  $^{2}$  = (1), which is related to the ΖT length of the junction. The above analytic expressions provide a convenient m eans for analyzing the length characteristic of S and Z T in nanojunctions.

Before turning to the detailed discussion on the therm oelectric properties in nano junctions, we must draw attention to the reason why nano junctions display material properties for S and Z T. The Seebeck coe cients are directly related to the transm ission functions, which are determ ined by the electronic structures of the crystalm aterials irrelevant to the size and shape of the material, leading to the material properties for S. Furtherm ore, the conductance and the combined therm al conductance

= el + ph are proportional to the contact surface and inversely proportional to the length scale in the bulk crystalm aterials, which leads to the material properties for Z T due to the cancelation of the geometric factors in the conductance and the combined therm alconduc-; tance . However, whether the therm collectric materials in nano junctions remain to display material properties or show junction properties have not yet been fully realized.



FIG.1: (color online) A kanethiol junctions at  $V_B = 0.01 \text{ V}$  for C<sub>4</sub> [solid (black) lines], C<sub>6</sub> [dotted-dash (red) lines], and C<sub>8</sub> [dash (blue) lines]: (a) the Seebeck coe cient S vs. T; (b) the electron therm alconductivity <sub>el</sub> and the electric conductance

(inset) vs. T; (c) the phonon them al conductance  $_{\rm ph}$  vs. T; and (d) the log-log plot of Z T vs. T (inset shows the case of neglecting the them al conductance  $_{\rm ph}$  = 0).



FIG. 2: (color online) A lum inum atom ic junctions at  $V_B = 0.01 V$  for 1 Al [solid (black) lines], 2 Al [dotted-dash (red) lines], 3 Al [dash (blue) lines], and 4 Al [dot-dot-dash (green) lines]: (a) the Seebeck coe cient S vs. T and the schem atic of 3-A latom ic chain and its energy diagram (inset) where the Al Albond distance is about 6:3 a u; (b) the electron thermal conductance el and the electrical conductivity (inset) vs. T; (c) the phonon thermal conductivity ph vs. T; (d) the log-log plot of ZT vs. T (inset shows the case of neglecting the thermal conductance ph = 0).

Now, let us look closely into the properties of S and Z T in the linear response regime at low temperatures with T =  $T_L$  =  $T_R$  for the two catalogs of nanojunctions: the (insulating) alkanethic1 junctions and the (m etallic) alum inum atom ic junctions.

First, we exam ine the dependence of S and Z T on the lengths of the alkanethiol junctions [17]. A lkanethiols  $[CH_3 (CH_2)_{n-1} SH$ , denoted as  $C_n$ ] are a good example of reproducible junctions which can be fabricated [18, 19]. It has been well established that the non-resonant tunneling is the main conduction mechanism in the  $C_n$  junc-

tions. As shown in the inset of Fig. 2(b), the conductance is small, insensitive to temperatures, and decreases exponentially with the length of the molecules, as  $_0 \exp$  ( l), where l is the length of C<sub>n</sub> m olecule and 0:78A <sup>1</sup> [20, 21, 22, 23, 24]. By exploiting the periodicity in the  $(CH_2)_2$  group of the  $C_n$  chains, the wave functions of the  $C_n$  junctions are calculated by a simple scaling argument, leading to exponential scaling in the transmission functions (E). It must be noted that the Seebeck coe cients are proportional to  $\frac{(0) - (0)E}{(1)}$ . Consequently, the Seebeck coe cient does not show dependence on the length [see Fig. 1(a)] of the  $C_n$  junctions due to the cancelation of the exponential scaling behavior in () for insulating m olecules. We have noted that the cancelation may not be complete in the real experiments; thus, the Seebeck coe cients could possibly show weak length dependence due to other e ects [1, 12]. In such case, the Seebeck coe cients mostly display material properties.

Let us now investigate the length-dependence of Z T for the  $C_n$  junctions. We predict that the  $C_n$  junctions display the material properties when T  $T_0$  and display the junction properties when T  $T_0$ . The reason for this is due to di erent scaling behaviors on the length characteristics of the junctions for the electron and phonon therm alconductance and the competition between them .  $T_0$ , the electron transport dom inates the When T  $S^2T = e_1$ . As shown therm al current, and thus Z T in the inset of Fig. 1(d), ZT is independent from the lengths of C<sub>n</sub> molecules and displays material properties. This result can be explained quite naturally by the cancelation of the exponential scaling in and el because both the electric current (with conductance ) and the electron therm alcurrent (with therm alconductance el) are conveyed by electron transport. W hen T Το, the phonon transport dom inates the therm alcurrent and  $S^2T = ph$ . As shown in the main body of thus Z T Fig. 1 (d),  $ZT / l^2 exp$  ( 1) because of / exp ( 1) [see the inset of Fig. 1 (b)], and  $_{ph} / 1^2$  [see Fig. 1 (c)]. In this case, Z T displays junction properties.

Finally, we will exam ine the dependence of S and Z T on the lengths of the metallic alum inum (Al) atom ic junctions [17]. An Alatom ic chain is an ideal testbed for studying the charge transport at the atom -scale level [see the inset of Fig. 2 (a) for a schem atic of the alum inum atom ic junction] [25, 26, 27, 28]. This study has observed that S and Z T depend on the geom etric characteristic of the junctions and show the junction properties in any case, which is in sharp contrast to the  $C_n$  junctions. At a xed tem perature, it has been observed that Z T and the magnitude of S increase as the number of Alatom s increases, as shown in Figs. 2(a) and (d). The increase of the Seebeck coe cients is due to the increase of the slopes in the transmission functions at the Ferm i levels. The reason for this may be due to the strong hybridization between the electronic structures of atom s and the electrodes. The negative sign of the Seebeck coe cients indicates that the metallic Al atom ic junctions are n-

In conclusion, this study has raised and answered an in portant fundam ental question in therm oelectric nanojunctions: do the therm oelectric materials in nano junctions remain to display material properties or show junction properties? To answer this question, we have developed a theory with analytical expressions for S and Z T allied to a fully self-consistent st-principles calculation in the DFT fram ework. Using the insulating alkanethiol molecular junctions and metallic alum inum junction as examples, this study concludes that the therm oelectric quantities in nanojunctions do not necessarily display m aterial properties or junction properties. The m etallic atom ic chains reveal strong length characteristics related to the strong hybridization in the electronic structures between the atom s and electrodes, while the insulating m olecular w ires display strong m aterial properties due to the cancelation of exponential scalings in the DOSs. For S, the m etallic atom ic chains reveal strong length characteristics related to the strong interactions between the electronic structure of atom s and the electrodes, while the insulating molecular wires show independence from the lengths of m olecules, thus displaying strong m aterial properties due to the cancelation of exponential scalings in the density of states. It may be worth pointing out the cancelation m ay not be com plete in real experim ents due to other e ects; the important point is, the strong exponential scaling behavior with the lengths of the junctions should be canceled. For ZT, the atom ic wires remain to show strong junction properties. However, the length characteristics of the insulation molecular wires depends on a characteristic tem perature  $T_0 =$ = (1) around 10 K.W hen T  $T_{0}$ , where the electron transport dom inates the therm al current, the molecular junctions remain to show material properties. When T Tor where the phonon transport dom inates the therm al current, the molecular junctions display junction properties. The length characteristic of the C<sub>n</sub> m olecules is according to ZT / l<sup>2</sup> exp ( l). The di erent length-scaling behaviors between the therm al current conveyed by the electrons and the therm alcurrent conveyed by the phonons o er the key to the understanding of characteristic tem perature and the behavior of Z T . W e believe that this study is a substantial step tow ards the understanding of the therm oelectric properties in nano junctions, and we hope that this study will generate more experimental and theoretical explorations in the properties of them oelectric nano junctions.

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- 17 The alum inum (alkanethiol) junction consisted of an Al atom ic chain (a C4 molecule) sandwich between two Al (Au) electrodes that were modeled as electron jellium with 2 (r. 3). The following parameters were used rs for the junctions: the elective cross-section chosen was  $A = 23:1 a.u.^{2}$  (21:4 a.u.<sup>2</sup>) for the alum inum (alkanetiol) junction. The spectral densities of electrodes were evaluated using the longitudinal and transverse sound velocities for Al (Au),  $v_1 = 6:35$  (3.2)  $10^5$  cm /s and  $v_t =$ 3:1 (1:2)  $10^5$  cm /s, respectively. The Young's modulus of alum in im (alkanethiol) wire, Y ' 1:2  $10^{13}$  dyne/cm<sup>2</sup> (Y ' 2:3  $10^{12}$  dyne/cm<sup>2</sup>), was calculated with total energy calculations and was found to be alm ost independent of the length of the wires.
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E lectronic address: yuchangchen@m ail.nctu.edu.tw